

# MCF5282 Device Errata

Supports: MCF5281 and MCF5282

By: Microcontroller Division

This document identifies implementation differences between the MCF5282 processor and the description contained in the *MCF5282 ColdFire® Microcontroller User's Manual*. Refer to <http://freescale.com/coldfire> for the latest updates. The errata items listed in this document (summarized in [Table 1](#)) describe differences from the following documents:

- *MCF5282 ColdFire Microcontroller User's Manual*
- *ColdFire Microprocessor Family Programmer's Reference Manual*

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## Leakage Current on V<sub>DDPLL</sub> pin

All current MCF5282 devices are marked as L95M mask set. The date code on the marking can be used to determine which errata have been corrected on a particular device as shown in Table 1. The datecode format is XXXYYWW, where YY represents the year and WW represents the work week. The three leading digits can be ignored.

**Table 1. Summary of MCF5282 Errata**

Errata ID	Module Affected	Date Errata Added	Date Code Affected			Errata Title
			<XXX0324	XXX0324 to XXX0326	≥XXX0327	
1	PLL	03/18/03	Yes	No	No	Leakage current on V <sub>DDPLL</sub> pin
2	BDM	03/28/03	Yes	Yes	Yes	BDM load of SR does not enable stack pointer exchange
3	EMAC	03/28/03	Yes	Yes	No	Unexpected pipeline stall on EMAC load/store accumulator instruction
4	Cache	03/31/03	Yes	Yes	No	Incorrect cache size
5	Flash	04/09/03	Yes	Yes	No	Corrupted fetches from Flash
6	Cache	07/21/03	Yes	Yes	Yes	Possible cache corruption after setting CACR[CINV]
7	Cache	07/21/03	Yes	Yes	Yes	Incorrect operation of CACR[CFRZ]
8	FlexCAN	07/23/03	Yes	Yes	Yes	32-bit accesses to FlexCAN registers do not work properly
9	FEC	04/22/04	Yes	Yes	Yes	FEC receive buffer overrun in 10baseT
10	FEC	04/22/04	Yes	Yes	Yes	Concatenation of received frames in 10baseT
11	PLL	08/23/04	Yes	Yes	Yes	PLL does not lock when in "Normal PLL mode with external clock reference"
12	FEC	09/14/04	Yes	Yes	Yes	Late collision, retry limit, and underrun interrupts will not trigger on consecutive transmit frames
13	QADC	03/15/05	Yes	Yes	Yes	Possible QADC Command Conversion Word (CCW) table corruption
14	GPIO	01/06/06	Yes	Yes	Yes	GPIO inputs behave inappropriately when pull-down resistors larger than 10kΩ are used

# 1 Leakage Current on V<sub>DDPLL</sub> pin

## 1.1 Description

The MCF5282 exhibits a 65mA leakage current on the V<sub>DDPLL</sub> supply, regardless of chip configuration.

## 1.2 Workaround

No workaround.

DATECODES AFFECTED: XXX0323 and earlier

## 2 BDM Load of SR Does Not Enable Stack Pointer Exchange

### 2.1 Description

The V2 core used in the MCF5282 adds support for separate user and supervisor stack pointers. The hardware implements an active stack pointer and an “other\_stack\_pointer.” Whenever the operating mode of the processor changes (supervisor → user, user → supervisor), the processor hardware “exchanges” the active SP and the other SP.

This exchange operation does not work when the processor mode is changed by a write to the SR from the BDM port. The hardware in the processor core required to process the BDM load\_SR operation and enable the stack pointer exchange is missing.

The exchange works properly when the SR is changed through software.

### 2.2 Workaround

Use software for any operations that require exchanging the stack pointers.

DATECODES AFFECTED: All

## 3 Unexpected Pipeline Stall on EMAC Load/Store Accumulator Instruction

### 3.1 Description

An unexpected pipeline stall occurs for accumulator load and accumulator store instructions that immediately follow a load accumulator or MAC instruction.

Specifically, the operand execution pipeline (OEP) experiences a 2T pipeline stall when a load/store accumulator instruction enters the pipeline immediately after any load accumulator or MAC instruction. The pipeline is supposed to stall only if there is a store accumulator instruction immediately following a load or MAC instruction that updated the specified accumulator.

A simple example can be created to expose this problem:

```
mac.l ra,rb,acc0
```

```
mac.l rc,rd,acc0
```

## Incorrect Cache Size

```
mov.l acc1,rx
```

In the above example, the store of acc1 (mov.l acc1,rx) should not experience any stall since that accumulator is not being updated. In the current V2 + EMAC implementation, it incorrectly stalls for two cycles.

### NOTE

The operation of the instructions is correct. The problem is that the expected timing is not met.

## 3.2 Workaround

No workaround.

DATECODES AFFECTED: XXX0326 and earlier

# 4 Incorrect Cache Size

## 4.1 Description

The MCF5282 operates as if it were connected to an 8KB cache; however, the cache size is in fact 2KB. Once the 2KB cache is full, the cache controller can have erroneous hits in the cache space resulting in data and/or instruction corruption.

## 4.2 Workaround

Do not enable the cache.

DATECODES AFFECTED: XXX0326 and earlier

# 5 Corrupted Fetches from Flash

## 5.1 Description

Leaving bit 6 in the FLASHBAR register cleared can cause corrupted fetches from the MCF5282's internal Flash. For datecodes after XXX0327, the bit is hardwired high to prevent the corrupted accesses.

## 5.2 Workaround

Set bit 6 in the FLASHBAR. This will prevent the corrupted fetches.

DATECODES AFFECTED: XXX0326 and earlier

## 6 Possible Cache Corruption After Setting CACR[CINV]

### 6.1 Description

The cache on the MCF5282 was enhanced to function as a unified data and instruction cache, an instruction cache, or an operand cache. The cache function and organization is controlled by the cache control register (CACR). The CINV (Bit 24 = cache invalidate) bit in the CACR causes a cache clear. If the cache is configured as a unified cache and the CINV bit is set, the scope of the cache clear is controlled by two other bits in the CACR, INVI (BIT 21 = CINV instruction cache only) and INVD (BIT 20 = CINV data cache only). These bits allow the entire cache, just the instruction portion of the cache, or just the data portion of the cache to be cleared. If a write to the CACR is performed to clear the cache (CINV = BIT 24 set) and only a partial clear will be done (INVI = BIT 21 or INVD = BIT20 set), then cache corruption may occur.

### 6.2 Workaround

All loads of the CACR that perform a cache clear operation (CINV = BIT 24) should be followed immediately by a NOP instruction. This avoids the cache corruption problem.

DATECODES AFFECTED: All

## 7 Incorrect Operation of CACR[CFRZ]

### 7.1 Description

The cache on the ColdFire V2 is controlled by the cache control register (CACR). When CACR[CFRZ] is set, the cache freeze function is enabled and no valid cache array entry will be displaced. However, this feature does not work as specified, sometimes allowing valid lines to be displaced when CACR[CFRZ] is enabled.

This will not cause any corrupted accesses. However, there could be cache misses for data that was originally loaded into the cache but was subsequently deallocated even though the CACR[CFRZ] bit was set.

Also, incoherent cache states are possible when a frozen cache is cleared via the CINV (bit 24 = cache invalidate) bit in the CACR.

### 7.2 Workaround

- Unfreeze the cache by clearing CACR[CFRZ] when invalidating the cache using the CACR[CINV] bit.
- Use the internal SRAM to store critical code/data if the system cannot handle a potential cache miss.

DATECODES AFFECTED: All

## 8 32-bit Accesses to FlexCAN Registers Do Not Work Properly

### 8.1 Description

Since the FlexCAN was originally designed for 16-bit architectures, all 32-bit register accesses are broken down into two back-to-back 16-bit accesses. However, the timing for the back-to-back accesses is incorrect and leads to corruption of the second 16-bit read or write.

### 8.2 Workaround

When reading or writing to the 32-bit RxMASK registers, use two 16-bit accesses instead of a single 32-bit access.

DATECODES AFFECTED: All

## 9 FEC Receive Buffer Overrun in 10BaseT Mode

### 9.1 Description

When the FEC is connected to a 10BaseT network, if length of the data stored in a descriptor is not evenly divisible by 16 (not line-aligned), then the FEC will write extra lines at the end of the buffer—the entire line that contains the last valid data is written and at least one extra line, but up to four lines after the end of the valid data can also be written. In most cases this is not a problem, since the extra lines of data still fall within the limits of the buffer. However, if the valid data ends near the end of the buffer, then the extra lines written by the FEC might be outside of the data buffer. This leads to corruption of the next buffer, descriptor, data, or code stored in the adjacent memory.

For example, as shown in [Figure 1](#), if the max buffer size is programmed to 0x600 and a frame that is 0x5F8 bytes long is received, then a line is written starting at buffer start + 0x5F0. The first half of the line at buffer start + 0x5F0 is valid frame data that should be processed by the FEC driver; the second half of the line is additional data that is written because the FEC will only write complete lines. This data should be ignored by the FEC driver. So far, this is correct FEC behavior as originally specified. However, the FEC will repeat the last line of valid data a number of times. The line at buffer start + 0x600 will be written, and as many as three additional lines beyond the end of the data buffer could be written.

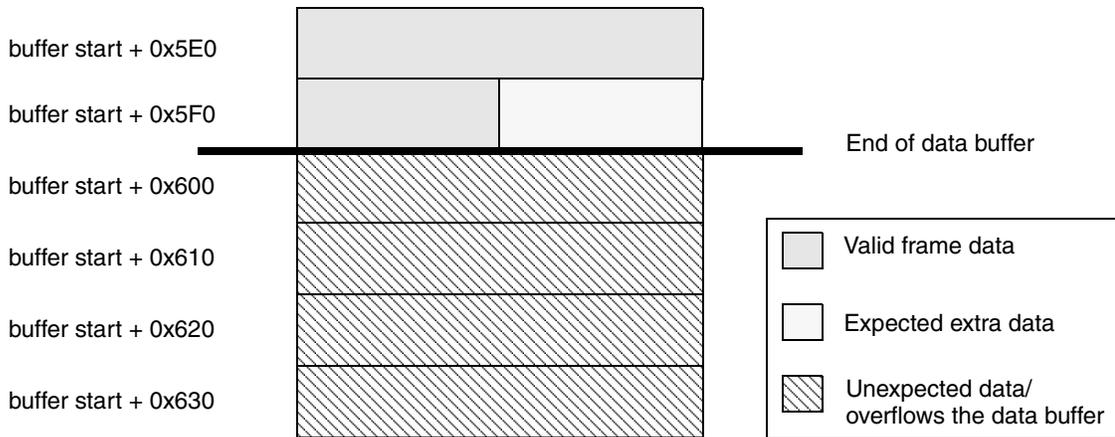


Figure 1. Buffer Overrun Example

## 9.2 Workaround

There are three independent workarounds:

1. Only use 100BaseT.
2. Allocate extra lines for the receive data buffers. The actual allocated memory for each buffer should be equal to the receive buffer size programmed in the FEC's EMRBR register plus four lines (16 byte-sized lines).
3. Program the data buffer size one line larger than the max packet size (data buffer size = EMRBR + 0x40).

DATECODES AFFECTED: All

# 10 Concatenation of Received Frames in 10BaseT Mode

## 10.1 Description

When the FEC is connected to a 10BaseT network, sometimes the FEC will combine the data from multiple frames to generate a single frame. The data from the frames is received correctly, but the frame boundary is not reported correctly. This causes the descriptor to report the length as the data length for all of the concatenated frames added together. The incorrect data length might exceed the max frame length programmed in the RCR[MAX\_FL] field.

When TCP is used as a transport mechanism, this errata will manifest itself as lost packets and reduced throughput. Data will still ultimately be received correctly, because TCP will request retransmission of bad packets. However, UDP does not include any mechanism for packet retransmission, as it is a 'send and forget' protocol. Consequently, while UDP should be able to identify a packet that is received incorrectly (because its checksum will fail), higher level software in the protocol stack must be capable of requesting retransmission to work around this errata.

## 10.2 Workaround

Higher level Ethernet layer code should compare the length reported by the descriptor to the length included in its header. If the lengths do not match, then the packet should be truncated or discarded as needed. The protocol stack must be responsible for requesting retransmission of any frames that are discarded due to the data length mismatch.

DATECODES AFFECTED: All

## 11 PLL Does Not Lock when in “Normal PLL mode with External Clock Reference”

### 11.1 Description

During a power on reset, if the CLKMOD[1:0] = 10 setting is used (normal PLL mode with external clock reference), then the MCF5282 PLL does not lock and the device never comes out of reset.

### 11.2 Workaround

When configuring the PLL for “Normal PLL mode with external clock reference,” tie CLKMOD1 to  $\overline{\text{RSTI}}$  and not straight to 3.3V. This allows the PLL to correctly detect the desired operating mode and lock.

DATECODES AFFECTED: All

## 12 Late Collision, Retry Limit, and Underrun Interrupts Will Not Trigger on Consecutive Transmit Frames

### 12.1 Description

The late collision (LC), retry limit (RL), and underrun (UN) interrupts will not trigger on consecutive transmit frames. For example, if back-to-back frames cause a transmit underrun, only the first frame will generate an underrun interrupt. No other underrun interrupts will be generated until a frame is transmitted that does not underrun or the FEC is reset.

### 12.2 Workaround

Since late collision, retry limit, and underrun errors are not directly correlated to a specific transmit frame, in most cases a workaround for this problem is not needed. If a workaround is required, then there are two independent workarounds:

- Ensure that a correct frame is transmitted after a late collision, retry limit, or underrun errors are detected.
- Perform a soft reset of the FEC by setting ECR[RESET] when a late collision, retry limit, or underrun errors are detected.

DATECODES AFFECTED: All

## 13 Possible QADC Command Conversion Word (CCW) table corruption

### 13.1 Description

A CCW Table location may be corrupted by writing any other CCW or Results table location while any Queue is active. If a CCW table or Result table write occurs while either Queue is active, then it is possible for another CCW location to be corrupted. This bug only occurs if the write cycle is simultaneous with the Queue State Machine reading the next CCW location. The odds of this happening are 1 in the number of clocks in a conversion.

### 13.2 Workaround

There are three possible workarounds:

1. Make sure that both Queues have completed or are paused before updating a CCW Table or Result Table location.
2. If workaround #1 is not possible, then the application code can monitor the CWP bits in the QASR0. Just after it changes, it is safe to write a CCW Table or Result Register location. The safe time is equal to the input sample time of the next conversion (4-18 QCLKs).
3. If workarounds #1 and #2 are not possible, then it is possible to update a CCW or Result Register location while a queue is active by going through the following sequence:
  - Read Status Register 0 and save the CWP value
  - Perform the write
  - Read CCW locations pointed to by CWP and CWP+1 to check if they are corrupted
  - Fix any of the possibly corrupted locations

The above sequence should be safe, because if a CCW location is corrupted, it will not be used until a queue wraps around back to this CCW. The user has one conversion time to perform the corruption checks and fixes. There should be plenty of time to do this without worrying about another CCW corruption.

## 14 GPIO inputs behave inappropriately when pull-down resistors larger than 10k $\Omega$ are used

### 14.1 Description

GPIO inputs that shouldn't have internal pull-ups, behave as if internal pull-ups are enabled when pull-down resistors larger than 10k $\Omega$  are used

To achieve 5V tolerance for the I/O pads, a pull-up device is used in order to latch the input value of the pads while protecting internal circuitry to direct exposure to potentials above 3.6V. These pull-up devices are not disabled once stimulus is removed and a pull-down resistor value larger than 10k $\Omega$  is used.

### 14.2 Workaround

In order to disable the pull-up, a pull-down resistor value of 10k $\Omega$  or less is needed.

DATECODES AFFECTED: All

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